Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
09/633,782	LEE ET AL.		
Examiner	Art Unit		
HOAN C. NGUYEN	2871		

		<u></u>		
SEARCHED				
Class	Subclass	Date	Examiner	
349	43	9/8/2005	CHN	
257	59	9/8/2005	CHN	
257	72	9/8/2005	CHN	
345	92	9/8/2005	CHN	
	,			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
east search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	9/8/2005	CHN	
,			